## Application/Control No. Applicant(s)/Patent Under Reexamination 10/780,163 MOCK ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Alexander O. Williams 2826 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,307,755 B1 10-2001 Williams et al. 361/813 \* US-5,166,098 11-1992 Micic et al. 29/855 В \* US-6,084,291 07-2000 Fujimori, Yoshikazu С 257/668 US-6,459,148 B1 10-2002 Chun-Jen et al. 257/692 D US-Ε US-F US-G US-Н US-US-J US-K US-US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY 6-252334 09-1994 Ν Japan 5-47980 02-1993 0 Japan 2001-298142 10-2001 Ρ Japan Honda et al. Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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